

## N-Channel Reduced $Q_g$ , Fast Switching MOSFET

### DESCRIPTION

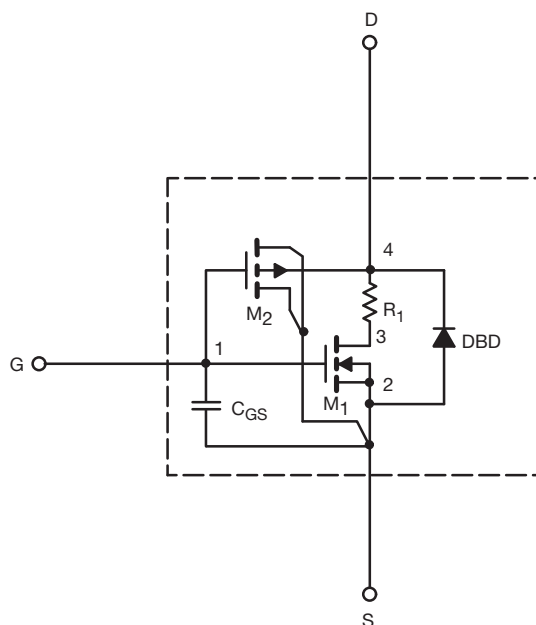
The attached SPICE model describes the typical electrical characteristics of the n-channel vertical DMOS. The subcircuit model is extracted and optimized over the - 55 °C to 125 °C temperature ranges under the pulsed 0 V to 5 V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched  $C_{gd}$  model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

### CHARACTERISTICS

- N-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the - 55 °C to + 125 °C Temperature Range
- Model the Gate Charge

### SUBCIRCUIT MODEL SCHEMATIC



### Note

- This document is intended as a SPICE modeling guideline and does not constitute a commercial product datasheet. Designers should refer to the appropriate datasheet of the same number for guaranteed specification limits.



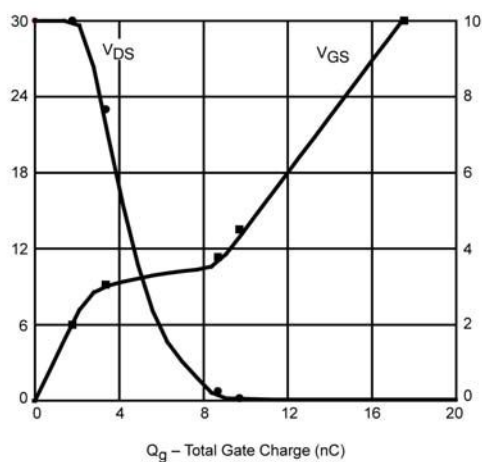
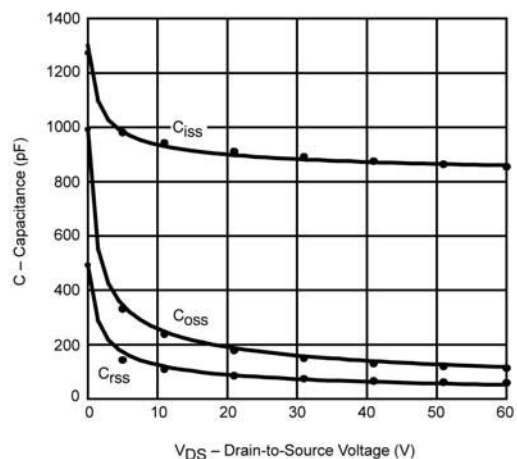
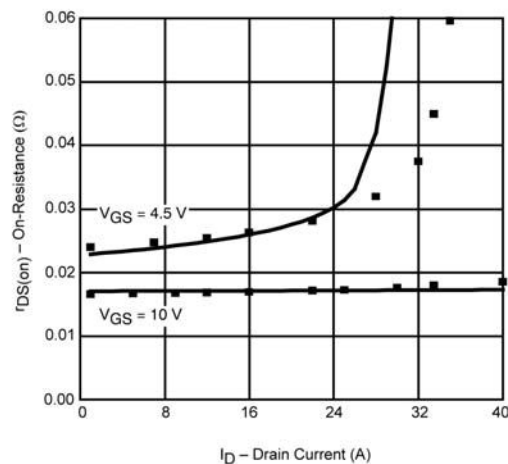
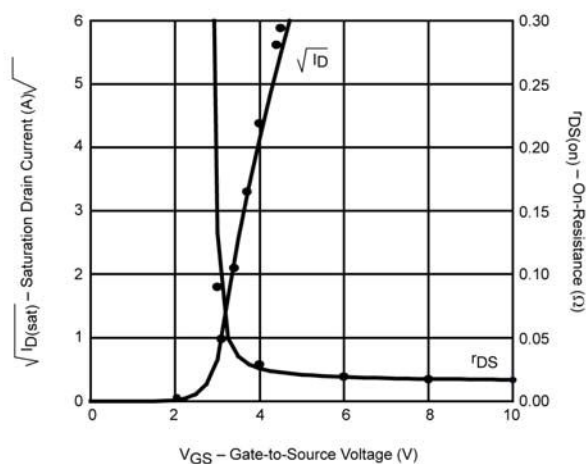
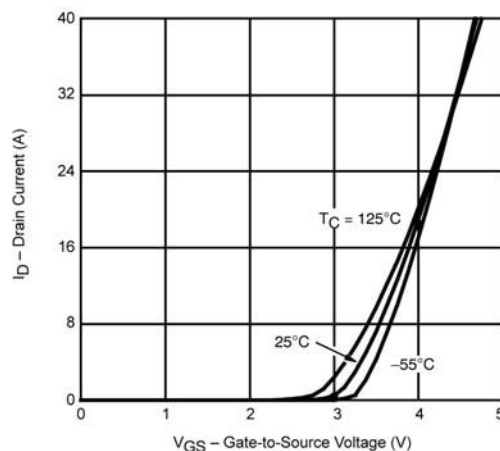
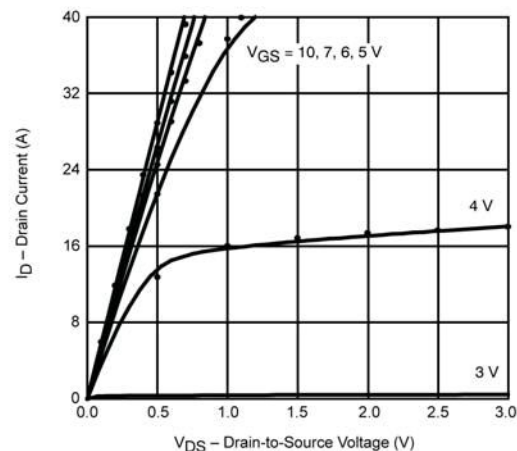
SPECIFICATIONS ( $T_J = 25\text{ }^{\circ}\text{C}$ , unless otherwise noted)					
PARAMETER	SYMBOL	TEST CONDITIONS	SIMULATED DATA	MEASURED DATA	UNIT
<b>Static</b>					
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$	1.95	-	V
On-State Drain Current <sup>a</sup>	$I_{D(on)}$	$V_{DS} \geq 5\text{ V}$ , $V_{GS} = 10\text{ V}$	248	-	A
Drain-Source On-State Resistance <sup>a</sup>	$R_{DS(on)}$	$V_{GS} = 10\text{ V}$ , $I_D = 6\text{ A}$	0.017	-	$\Omega$
		$V_{GS} = 10\text{ V}$ , $I_D = 6\text{ A}$ , $T_J = 125\text{ }^{\circ}\text{C}$	0.026	-	
		$V_{GS} = 10\text{ V}$ , $I_D = 6\text{ A}$ , $T_J = 175\text{ }^{\circ}\text{C}$	0.032	-	
		$V_{GS} = 4.5\text{ V}$ , $I_D = 5.1\text{ A}$	0.023	-	
Forward Transconductance <sup>a</sup>	$g_{fs}$	$V_{DS} = 15\text{ V}$ , $I_D = 6\text{ A}$	22	-	S
Diode Forward Voltage <sup>a</sup>	$V_{SD}$	$I_S = 1.7\text{ A}$ , $V_{GS} = 0\text{ V}$	0.8	-	V
<b>Dynamic<sup>b</sup></b>					
Total Gate Charge	$Q_g$	$V_{DS} = 30\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 6\text{ A}$	17.5	-	nC
Gate-Source Charge	$Q_{gs}$		3.4	-	
Gate-Drain Charge	$Q_{gd}$		5.3	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 30\text{ V}$ , $R_L = 30\text{ }\Omega$ $I_D = 1\text{ A}$ , $V_{GEN} = 10\text{ V}$ , $R_g = 6\text{ }\Omega$	22	-	ns
Rise Time	$t_r$		25	-	
Turn-Off Delay Time	$t_{d(off)}$		42	-	
Fall Time	$t_f$		48	-	
Source-Drain Reverse Recovery Time	$t_{rr}$	$I_F = 1.7\text{ A}$ , $dI/dt = 100\text{ A}/\mu\text{s}$	39	-	

**Notes**

- a. Pulse test; pulse width  $\leq 300\text{ }\mu\text{s}$ , duty cycle  $\leq 2\%$ .  
b. Guaranteed by design, not subject to production testing.



## COMPARISON OF MODEL WITH MEASURED DATA ( $T_J = 25^\circ\text{C}$ , unless otherwise noted)



### Note

- Dots and squares represent measured data.